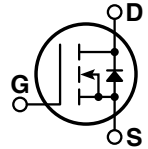


Super Junction MOSFET



- Ultra low $R_{DS(ON)}$
- Ultra Low Gate Charge, Q_g
- Popular SOT-227 Package
- Low Miller Capacitance
- Avalanche Energy Rated
- N-Channel Enhancement Mode



Unless stated otherwise, Microsemi discrete MOSFETs contain a single MOSFET die. This device is made with two parallel MOSFET die. It is intended for switch-mode operation. It is not suitable for linear mode operation.

MAXIMUM RATINGS

All Ratings: $T_C = 25^\circ\text{C}$ unless otherwise specified.

| Symbol | Parameter | APT31N80JC3 | UNIT |
|----------------|--|-------------|---------------------|
| V_{DSS} | Drain-Source Voltage | 800 | Volts |
| I_D | Continuous Drain Current @ $T_C = 25^\circ\text{C}$ | 31 | Amps |
| I_{DM} | Pulsed Drain Current ^① | 93 | |
| V_{GS} | Gate-Source Voltage Continuous | ± 20 | Volts |
| V_{GSM} | Gate-Source Voltage Transient | ± 30 | |
| P_D | Total Power Dissipation @ $T_C = 25^\circ\text{C}$ | 833 | Watts |
| | Linear Derating Factor | 6.67 | W/ $^\circ\text{C}$ |
| T_J, T_{STG} | Operating and Storage Junction Temperature Range | -55 to 150 | $^\circ\text{C}$ |
| T_L | Lead Temperature: 0.063" from Case for 10 Sec. | 300 | |
| dv/dt | Drain-Source Voltage slope ($V_{DS} = 640\text{V}$, $I_D = 31\text{A}$, $T_J = 125^\circ\text{C}$) | 50 | V/ns |
| I_{AR} | Repetitive Avalanche Current ^⑦ | 17 | Amps |
| E_{AR} | Repetitive Avalanche Energy ^⑦ | 0.5 | mJ |
| E_{AS} | Single Pulse Avalanche Energy ^④ | 670 | |

STATIC ELECTRICAL CHARACTERISTICS

| Symbol | Characteristic / Test Conditions | MIN | TYP | MAX | UNIT |
|--------------|---|------|-------|-----------|---------------|
| BV_{DSS} | Drain-Source Breakdown Voltage ($V_{GS} = 0\text{V}$, $I_D = 500\mu\text{A}$) | 800 | | | Volts |
| $R_{DS(on)}$ | Drain-Source On-State Resistance ^② ($V_{GS} = 10\text{V}$, $I_D = 22\text{A}$) | | 0.125 | 0.145 | Ohms |
| I_{DSS} | Zero Gate Voltage Drain Current ($V_{DS} = 800\text{V}$, $V_{GS} = 0\text{V}$) | | 0.5 | 25 | μA |
| | Zero Gate Voltage Drain Current ($V_{DS} = 800\text{V}$, $V_{GS} = 0\text{V}$, $T_J = 150^\circ\text{C}$) | | | 250 | |
| I_{GSS} | Gate-Source Leakage Current ($V_{GS} = \pm 20\text{V}$, $V_{DS} = 0\text{V}$) | | | ± 200 | nA |
| $V_{GS(th)}$ | Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_D = 2\text{mA}$) | 2.10 | 3 | 3.9 | Volts |

 **CAUTION:** These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

Microsemi Website - <http://www.microsemi.com>

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DYNAMIC CHARACTERISTICS

APT31N80JC3

| Symbol | Characteristic | Test Conditions | MIN | TYP | MAX | UNIT |
|--------------|------------------------------|---|-----|------|-----|---------|
| C_{iss} | Input Capacitance | $V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1\text{ MHz}$ | | 4510 | | pF |
| C_{oss} | Output Capacitance | | | 2050 | | |
| C_{rss} | Reverse Transfer Capacitance | | | 110 | | |
| Q_g | Total Gate Charge ③ | $V_{GS} = 10V$ $V_{DD} = 400V$ $I_D = 31A @ 25^\circ C$ | | 180 | 355 | nC |
| Q_{gs} | Gate-Source Charge | | | 22 | | |
| Q_{gd} | Gate-Drain ("Miller") Charge | | | 90 | | |
| $t_{d(on)}$ | Turn-on Delay Time | RESISTIVE SWITCHING $V_{GS} = 10V$ $V_{DD} = 400V$ $I_D = 31A @ 125^\circ C$ $R_G = 2.5\Omega$ | | 25 | | ns |
| t_r | Rise Time | | | 15 | | |
| $t_{d(off)}$ | Turn-off Delay Time | | | 70 | 80 | |
| t_f | Fall Time | | | 6 | 9 | |
| E_{on} | Turn-on Switching Energy ⑥ | INDUCTIVE SWITCHING @ 25^\circ C $V_{DD} = 533V, V_{GS} = 15V$ $I_D = 31A, R_G = 5\Omega$ | | 615 | | μJ |
| E_{off} | Turn-off Switching Energy | | | 530 | | |
| E_{on} | Turn-on Switching Energy ⑥ | INDUCTIVE SWITCHING @ 125^\circ C $V_{DD} = 533V, V_{GS} = 15V$ $I_D = 31A, R_G = 5\Omega$ | | 1025 | | |
| E_{off} | Turn-off Switching Energy | | | 580 | | |

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

| Symbol | Characteristic / Test Conditions | MIN | TYP | MAX | UNIT |
|----------|--|-----|-----|-----|---------|
| I_S | Continuous Source Current (Body Diode) | | | 31 | Amps |
| I_{SM} | Pulsed Source Current ① (Body Diode) | | | 93 | |
| V_{SD} | Diode Forward Voltage ② ($V_{GS} = 0V, I_S = -31A$) | | 1 | 1.2 | Volts |
| t_{rr} | Reverse Recovery Time ($I_S = -31A, di_S/dt = 100A/\mu s, V_R = 400V$) | | 855 | | ns |
| Q_{rr} | Reverse Recovery Charge ($I_S = -31A, di_S/dt = 100A/\mu s, V_R = 400V$) | | 30 | | μC |
| dv/dt | Peak Diode Recovery dv/dt ⑤ | | | 6 | V/ns |

THERMAL CHARACTERISTICS

| Symbol | Characteristic | MIN | TYP | MAX | UNIT |
|-----------------|---------------------|-----|-----|------|--------------|
| $R_{\theta JC}$ | Junction to Case | | | 0.37 | $^\circ C/W$ |
| $R_{\theta JA}$ | Junction to Ambient | | | 62 | |

① Repetitive Rating: Pulse width limited by maximum junction temperature

② Pulse Test: Pulse width < 380 μs , Duty Cycle < 2%

③ See MIL-STD-750 Method 3471

④ Starting $T_j = +25^\circ C$, $L = 115.92mH$, $R_G = 25\Omega$, Peak $I_L = 3.4A$

⑤ $I_S = -31A$ $di_S/dt = 100A/\mu s$ $v_R = 480V$ $T_j = 125^\circ C$

⑥ Eon includes diode reverse recovery. See figures 18, 20.

⑦ Repetitive avalanche causes additional power losses that can be calculated as $P_{AV} = E_{AR} \cdot f$

Microsemi reserves the right to change, without notice, the specifications and information contained herein.

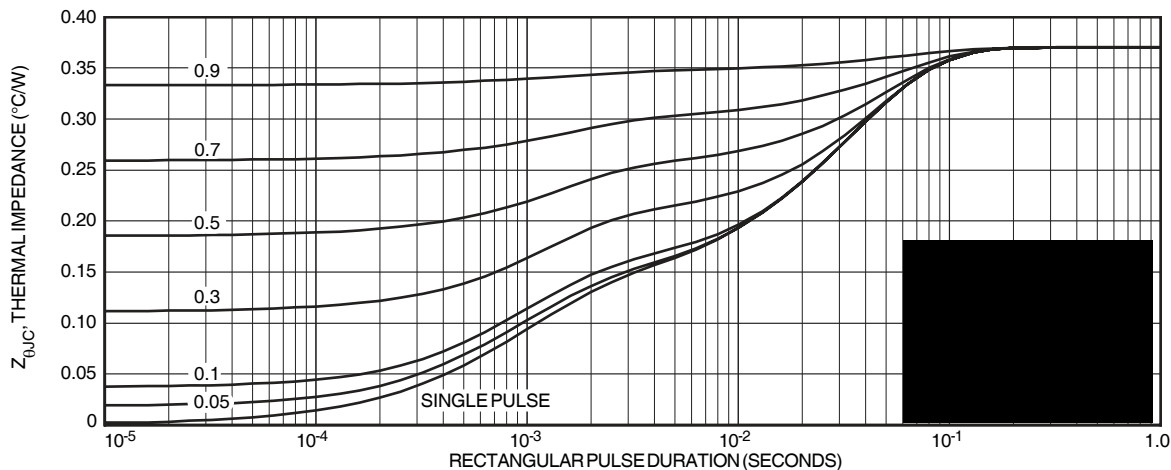


FIGURE 1, MAXIMUM EFFECTIVE TRANSIENT THERMAL IMPEDANCE, JUNCTION-TO-CASE vs PULSE DURATION

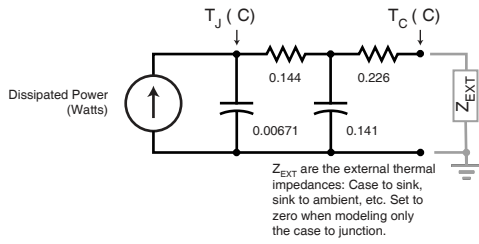


FIGURE 2, TRANSIENT THERMAL IMPEDANCE MODEL

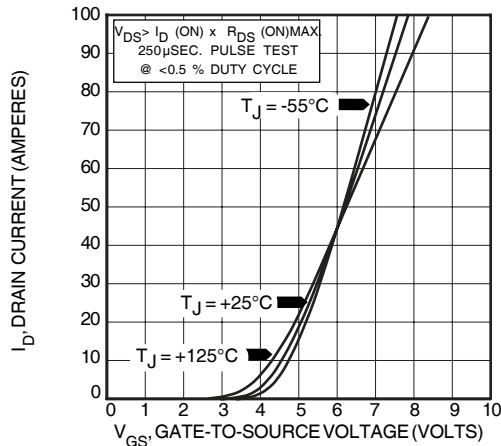


FIGURE 4, TRANSFER CHARACTERISTICS

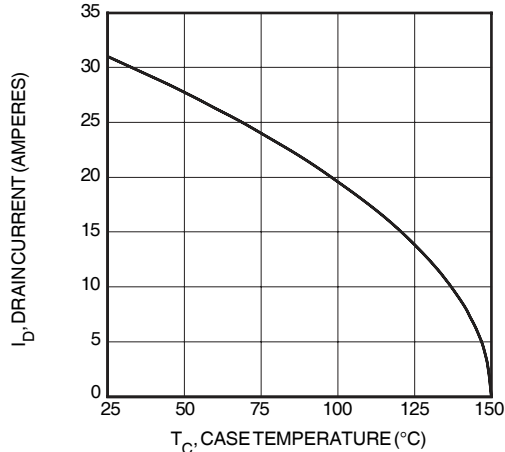


FIGURE 6, MAXIMUM DRAIN CURRENT vs CASE TEMPERATURE

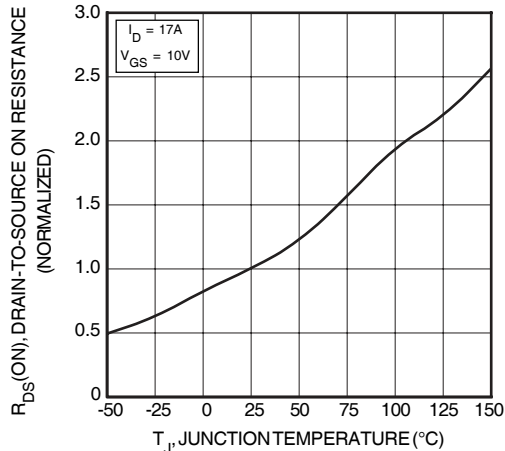


FIGURE 8, ON-RESISTANCE vs. TEMPERATURE

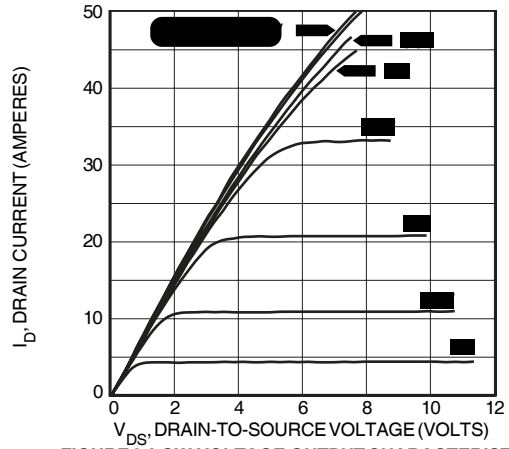


FIGURE 3, LOW VOLTAGE OUTPUT CHARACTERISTICS

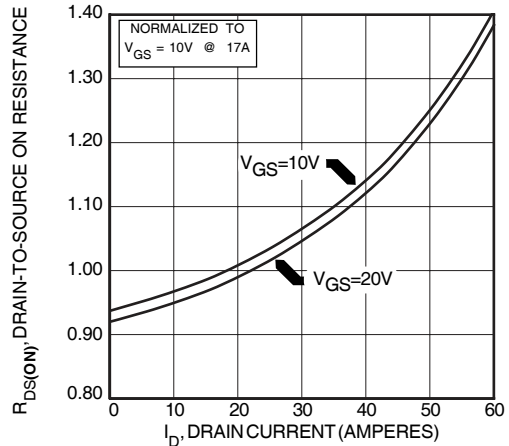


FIGURE 5, $R_{DS(ON)}$ vs DRAIN CURRENT

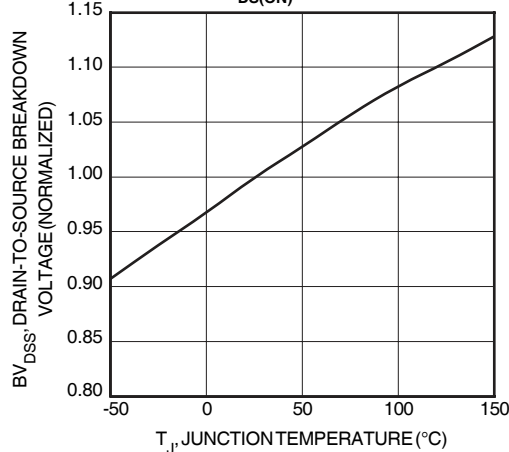


FIGURE 7, BREAKDOWN VOLTAGE vs TEMPERATURE

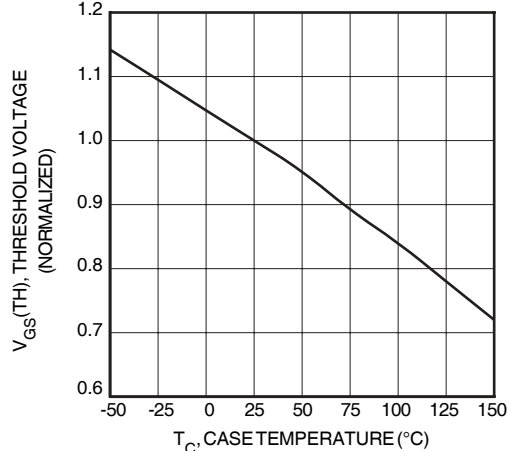


FIGURE 9, THRESHOLD VOLTAGE vs TEMPERATURE

I_D , DRAIN CURRENT (AMPERES)

Graph removed

V_{DS} , DRAIN-TO-SOURCE VOLTAGE (VOLTS)
FIGURE 10, MAXIMUM SAFE OPERATING AREA

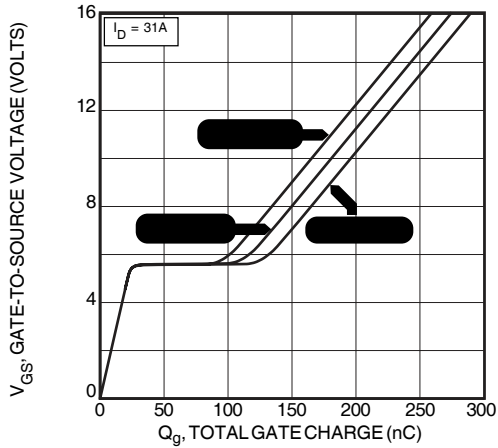


FIGURE 12, GATE CHARGES vs GATE-TO-SOURCE VOLTAGE

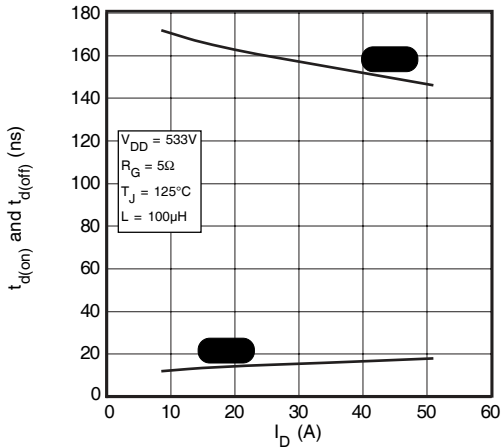


FIGURE 14, DELAY TIMES vs CURRENT

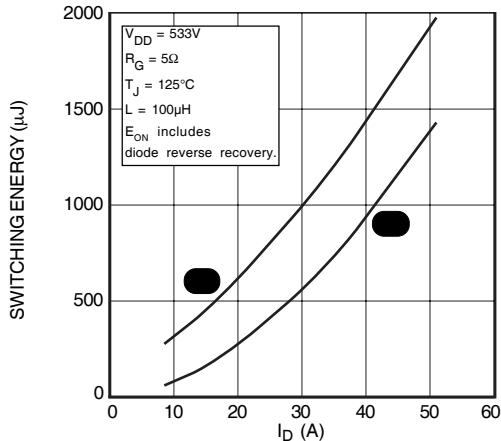


FIGURE 15, RISE AND FALL TIMES vs CURRENT

FIGURE 16, SWITCHING ENERGY vs CURRENT

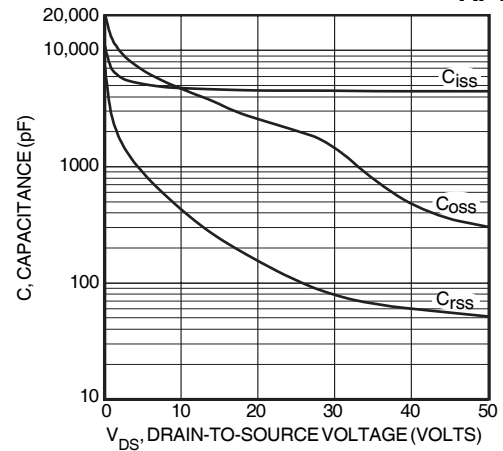
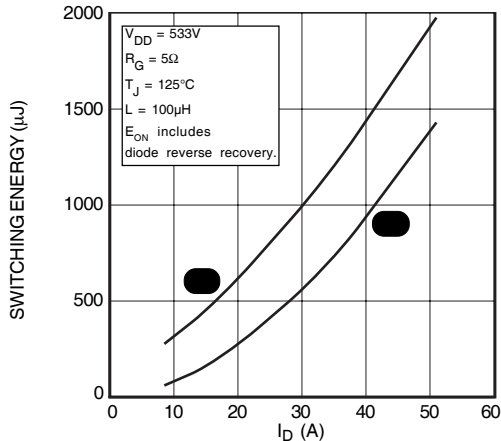


FIGURE 11, CAPACITANCE vs DRAIN-TO-SOURCE VOLTAGE

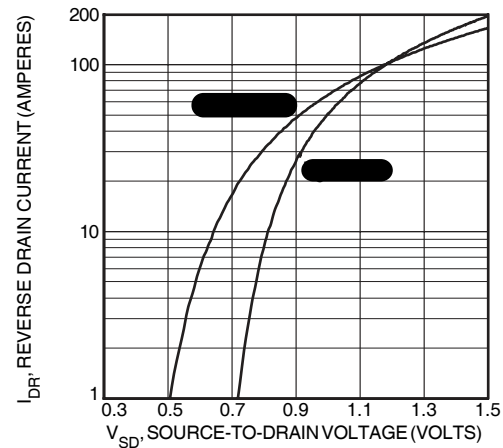


FIGURE 13, SOURCE-DRAIN DIODE FORWARD VOLTAGE

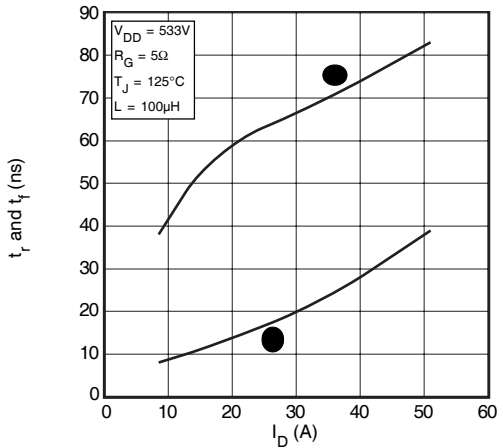


FIGURE 15, RISE AND FALL TIMES vs CURRENT

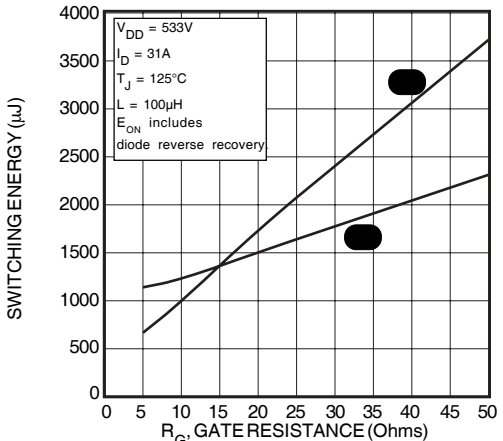


FIGURE 17, SWITCHING ENERGY VS. GATE RESISTANCE

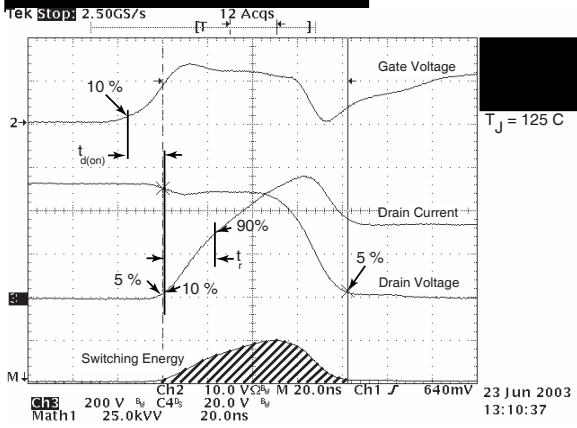


Figure 18, Turn-on Switching Waveforms and Definitions

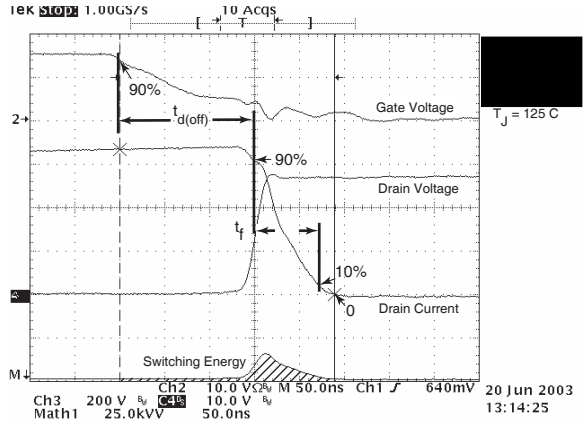


Figure 19, Turn-off Switching Waveforms and Definitions

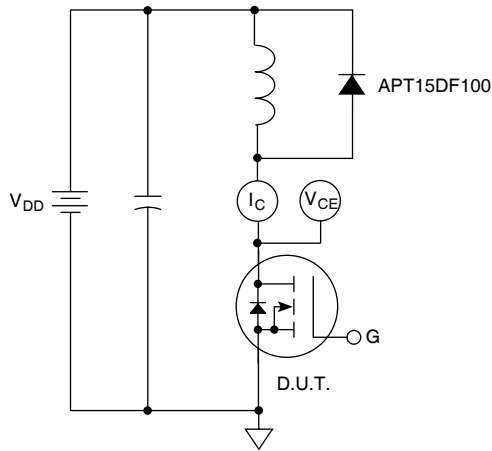
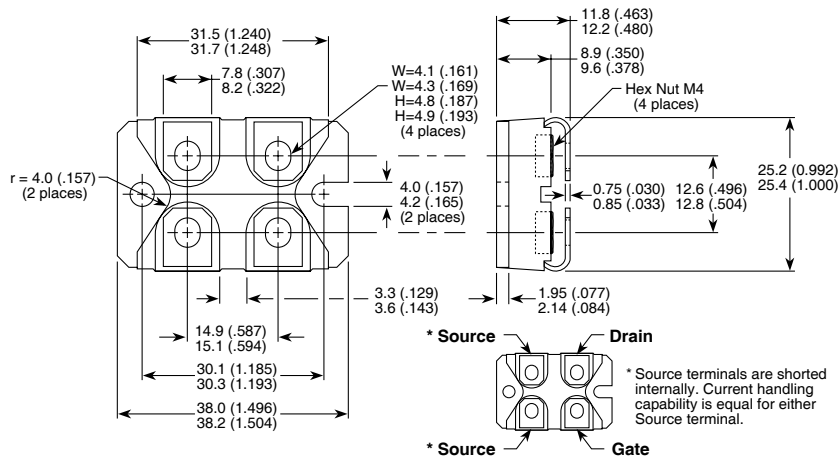


Figure 20, Inductive Switching Test Circuit

SOT-227 (ISOTOP®) Package Outline



Dimensions in Millimeters and (Inches)

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